

# XPX30T8U0FD

30V N-Channel Super Trench Power MOSFET

### Description

The XPX30T8U0FD uses advanced trench technology and design to provide excellent  $R_{DS(ON)}$  with low gate charge. It can be used in a wide variety of applications.

#### **General Features**

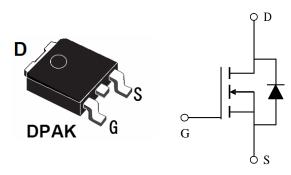
- High density cell design for ultra low Rdson
- Fully characterized Avalanche voltage and current
- Good stability and uniformity with high E<sub>AS</sub>
- Excellent package for good heat dissipation
- Special process technology for high ESD capability

#### Application

- Power switching application
- Hard switched and high frequency circuits
- Uninterruptible Power Supply

RoHS COMPLIANT

 $V_{DS} = 30V, I_D = 50A$ RDS(ON)=8.0mΩ (typ) @ VGS=10V RDS(ON)=10mΩ (typ) @ VGS=4.5V



#### Package Marking and Ordering Information

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
XPX30T8U0FD	XPX30T8U0FD	TO-252-2L	-	-	-

#### Absolute Maximum Ratings (Tc=25°Cunless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	VDS	30	V
Gate-Source Voltage	Vgs	±20	V
Drain Current-Continuous	Ι <sub>D</sub>	50	А
Drain Current-Continuous(Tc=100℃)	I <sub>D</sub> (100℃)	37	A
Pulsed Drain Current	I <sub>DM</sub>	200	A
Maximum Power Dissipation	PD	60	W
Drain Source voltage slope, $V_{DS} \leq 24 V$ ,	dv/dt	50	V/ns
Drain Source voltage slope, VDs $\leq$ 24 V, IsD <id< td=""><td>dv/dt</td><td>50</td><td>V/ns</td></id<>	dv/dt	50	V/ns
Derating factor		0.5	W/℃
Single pulse avalanche energy (Note 5)	E <sub>AS</sub>	100	mJ
Operating Junction and Storage Temperature Range	T <sub>J</sub> ,T <sub>STG</sub>	-55 To 175	°C
Thermal Resistance, Junction-to-Case <sup>(Note 2)</sup>	R <sub>θJC</sub>	2.5	°C/W



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#### Electrical Characteristics (T $_{c}$ =25 $^{\circ}C$ unless otherwise noted)

Parameter	Symbol	Condition	Min	Тур	Max	Unit	
Off Characteristics	·						
Drain-Source Breakdown Voltage	ource Breakdown Voltage BV <sub>DSS</sub> V <sub>GS</sub> =0V I <sub>D</sub> =250µA		30	33	-	V	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> =30V,V <sub>GS</sub> =0V	-	-	1	μA	
Gate-Body Leakage Current	I <sub>GSS</sub>	V <sub>GS</sub> =±20V,V <sub>DS</sub> =0V	-	-	±100	nA	
On Characteristics (Note 3)							
Gate Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> =V <sub>GS</sub> ,I <sub>D</sub> =250µA	1	1.5	2.5	V	
Drain-Source On-State Resistance		V <sub>GS</sub> =10V, I <sub>D</sub> =20A	-	8	11	mΩ	
	R <sub>DS(ON)</sub>	V <sub>GS</sub> =4.5V, I <sub>D</sub> =20A	-	10	16		
Forward Transconductance	<b>g</b> fs	V <sub>DS</sub> =5V,I <sub>D</sub> =20A		20	-	S	
Dynamic Characteristics (Note4)	·						
Input Capacitance	C <sub>lss</sub>		-	1868	-	PF	
Output Capacitance	C <sub>oss</sub>	V <sub>DS</sub> =15V,V <sub>GS</sub> =0V, F=1.0MHz	-	282	-	PF	
Reverse Transfer Capacitance	C <sub>rss</sub>		-	210	-	PF	
Switching Characteristics (Note 4)							
Turn-on Delay Time	t <sub>d(on)</sub>		-	10	-	nS	
Turn-on Rise Time	tr	V <sub>DD</sub> =15V,I <sub>D</sub> =20A	-	8	-	nS	
Turn-Off Delay Time	t <sub>d(off)</sub>	$V_{GS}$ =10V, $R_{GEN}$ =1.8 $\Omega$	-	25	-	nS	
Turn-Off Fall Time	t <sub>f</sub>		-	5	-	nS	
Total Gate Charge	Qg	V -10V(L-20A	-	32.3	-	nC	
Gate-Source Charge	Q <sub>gs</sub>	V <sub>DS</sub> =10V,I <sub>D</sub> =20A, V <sub>GS</sub> =10V	-	4.9	-	nC	
Gate-Drain Charge	Q <sub>gd</sub>	VGS-TUV	-	6.9	-	nC	
Drain-Source Diode Characteristics							
Diode Forward Voltage (Note 3)	V <sub>SD</sub>	V <sub>GS</sub> =0V,I <sub>S</sub> =20A	-	0.85	1.2	V	
Diode Forward Current (Note 2)	I <sub>S</sub>		-	-	50	Α	
Reverse Recovery Time	t <sub>rr</sub>	TJ = 25°C, I <sub>F</sub> = 20A	-	-	27	nS	
Reverse Recovery Charge	Qrr	di/dt = 100A/µs <sup>(Note3)</sup>	-	-	20	nC	
Forward Turn-On Time	t <sub>on</sub>	Intrinsic turn-on time is negl	igible (turi	n-on is do	minated b	y LS+LD)	

#### Notes:

- 1. Repetitive Rating: Pulse width limited by maximum junction temperature.
- **2.** Surface Mounted on FR4 Board,  $t \le 10$  sec.
- **3.** Pulse Test: Pulse Width  $\leq$  300µs, Duty Cycle  $\leq$  2%.
- 4. Guaranteed by design, not subject to production
- 5. EAS condition: Tj=25 $^\circ\!\mathrm{C}$ , V\_DD=15V,V\_G=10V,L=0.5mH, Rg=25 $\Omega$



V<sub>GS</sub>=4.5V

150

175

200

I<sub>D</sub>=20A

125

30

25° C

0.8

1.0

1.2

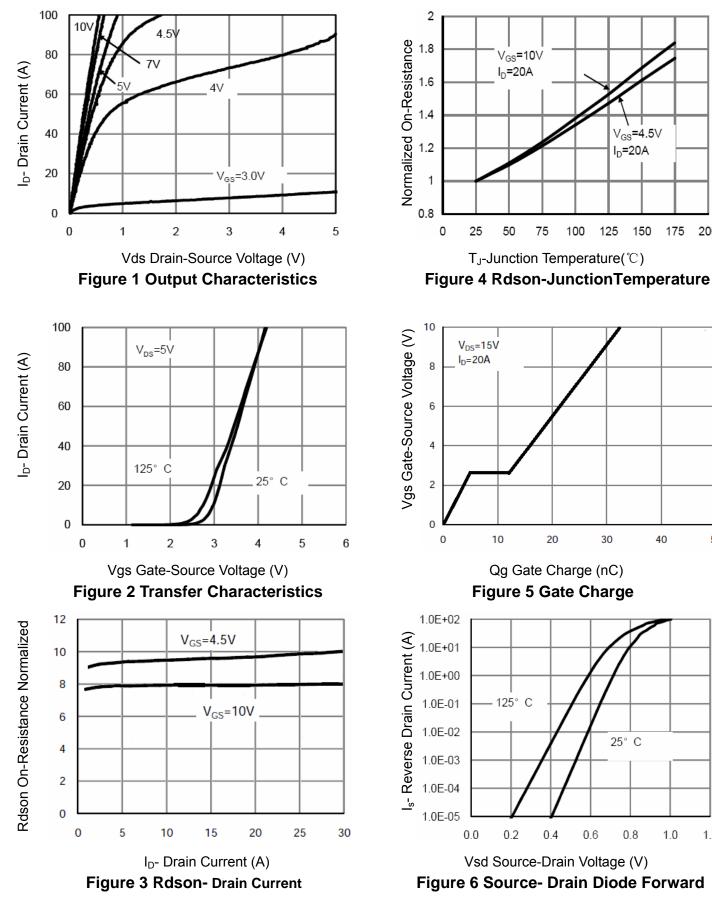
0.6

40

50

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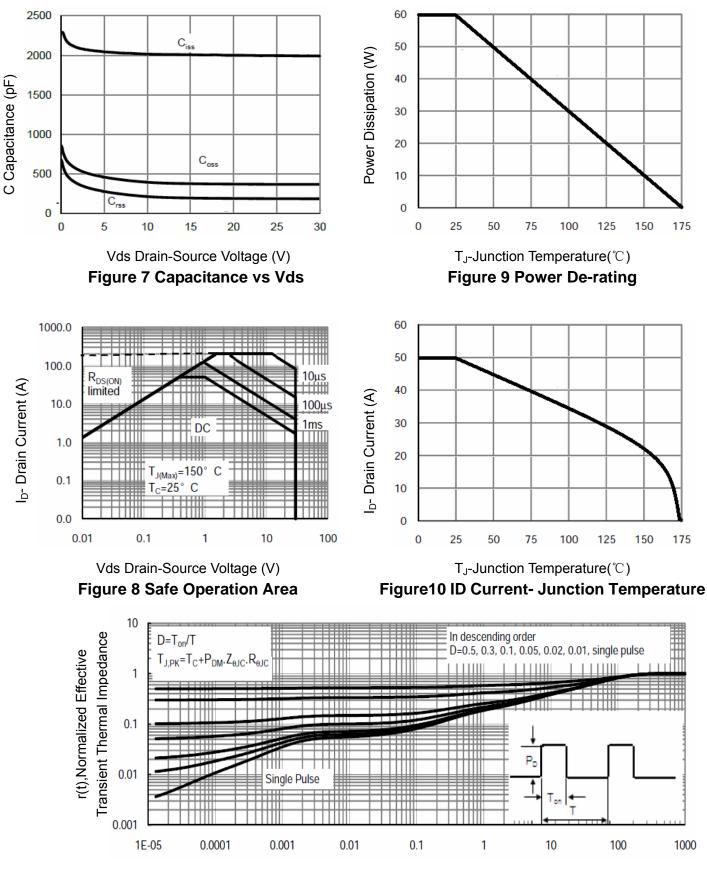
## **Typical Electrical and Thermal Characteristics (Curves)**





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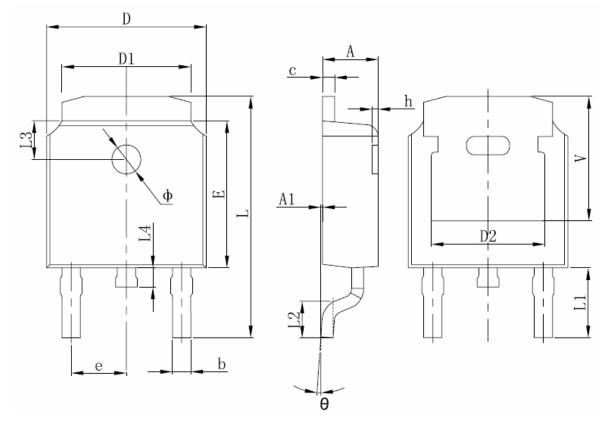
Square Wave Pluse Duration(sec)

Figure 11 Normalized Maximum Transient Thermal Impedance



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## **TO-252-2L Package Information**



Symbol	Dimensions	In Millimeters	Dimensions In Inches		
Symbol	Min.	Max.	Min.	Max.	
A	2.200	2.400	0.087	0.094	
A1	0.000	0.127	0.000	0.005	
b	0.635	0.770	0.025	0.030	
с	0.460	0.580	0.018	0.023	
D	6.500	6.700	0.256	0.264	
D1	5.100	5.460	0.201	0.215	
D2	4.830	REF.	0.190 REF.		
E	6.000	6.200	0.236	0.244	
e	2.186	2.386	0.086	0.094	
L	9.712	10.312	0.382	0.406	
L1	2.900	REF.	0.114 REF.		
L2	1.400	1.700	0.055	0.067	
L3	1.600	REF.	0.063 REF.		
L4	0.600	1.000	0.024	0.039	
Φ	1.100	1.300	0.043	0.051	
θ	0°	8°	0°	8°	
h	0.000	0.300	0.000	0.012	
V	5.250 REF.		0.207	REF.	



## 30V N-Channel Super Trench Power MOSFET

#### Flow (wave) soldering (solder dipping)

Product	Product Peak Temperature	
Pb device	<b>245℃±5</b> ℃	5sec <del>±</del> 1sec
Pb-Free device	<b>260</b> ℃+0/-5℃	5sec±1sec



This integrated circuit can be damaged by ESD UniverChip Corporation recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedure can cause damage. ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

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